TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TC7SL32F, TC7SL32FU

#### 2-INPUT OR GATE

The TC7SL32 is a low voltage operative  $C^2MOS$  2-INPUT OR GATE fabricated with silicon gate  $C^2MOS$  technology. Operating voltage ( $V_{CC}$  (opr)) is  $1\sim3V$  equivalent to 1pc or 2pcs of dry cell battery and it achives low power dissipation.

The internal circuit is composed of 3 stages including buffer output, which enables high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

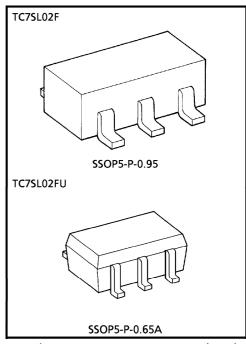
#### **FEATURES**

•	High Speed ······	$\cdots \cdots t_{pd} = 10$ ns (Typ.)
		at \/cc - 3\/

• Low Power Dissipation 
$$\cdots I_{CC} = 1\mu A$$
 (Max.) at  $Ta = 25^{\circ}C$ 

Balanced Propagation Delay Time ··· t<sub>pLH</sub>≒t<sub>pHL</sub>

• Low Voltage Operating············V<sub>CC</sub> (opr) = 1~3.6V

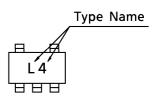


Weight SSOP5-P-0.95 : 0.016g (Typ.) SSOP5-P-0.65A : 0.006g (Typ.)

#### **MAXIMUM RATINGS**

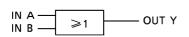
CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage Range	V <sub>C</sub> C	-0.5~5	V
DC Input Voltage	VIN	-0.5~V <sub>CC</sub> +0.5	٧
DC Output Voltage	Vout	-0.5~V <sub>CC</sub> +0.5	V
Input Diode Current	ΙΚ	± 20	mA
Output Diode Current	loк	± 20	mΑ
DC Output Current	IOUT	± 12.5	mA
DC V <sub>CC</sub> / Ground Current	ICC	± 25	mA
Power Dissipation	PD	200	mW
Storage Temperature	T <sub>stg</sub>	<b>- 65∼150</b>	°C
Lead Temperature (10s)	TL	260	°C

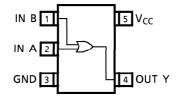
#### MARKING



#### LOGIC DIAGRAM

# PIN CONNECTION (TOP VIEW)





#### **RECOMMENDED OPERATING CONDITIONS**

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	Vcc	1~3.6	V
Input Voltage	VIN	0~V <sub>CC</sub>	V
Output Voltage	Vout	0~V <sub>CC</sub>	V
Operating Temperature	T <sub>opr</sub>	<b>- 40∼85</b>	°C
		$0 \sim 1000  (V_{CC} = 1.0V)$	
Input Rise and Fall Time	t <sub>r</sub> , t <sub>f</sub>	0∼ 500 (V <sub>CC</sub> = 1.5V)	ns
		0~ 400 (V <sub>CC</sub> = 3.0V)	

#### DC ELECTRICAL CHARACTERISTICS

TEST Ta = 25°C Ta = -40~85°C											
CHARACTERISTIC	SYMBOL	CIR- CUIT	TEST CONDITION		Vcc	MIN.	TYP.	MAX.	MIN.		∤ UNIT <b> </b>
High-Level Input	VIH				1.0	0.75	_	_	0.75	_	
Voltage		—	_		1.5	1.05	<b> </b>		1.05	-	V
					3.0	2.10	_	_	2.10		
Low-Level Input			_		1.0	—	—	0.25	—	0.25	v
Voltage	V <sub>IL</sub>	—			1.5	_	—	0.45	—	0.45	
Voltage					3.0	_	—	0.90	—	0.90	
	Vон				1.0	0.9	1.0	_	0.9	—	
I Carlo I accal			\	$I_{OH} = -20\mu A$	1.5	1.4	1.5	_	1.4	—	v
High-Level			$V_{IN} = V_{IH}$		3.0	2.9	3.0	_	2.9	—	
Output Voltage			or V <sub>IL</sub>	I <sub>OH</sub> = -1mA	1.5	1.07	1.23	_	0.99		
				$I_{OH} = -2.6 \text{mA}$	3.0	2.61	2.68	_	2.55	_	
	V <sub>OL</sub>		V <sub>IN</sub> = V <sub>IL</sub>	I <sub>OL</sub> = 20μA	1.0	_	0.0	0.1	_	0.1	V
					1.5	l —	0.0	0.1	—	0.1	
Low-Level					3.0	—	0.0	0.1	—	0.1	
Output Voltage				I <sub>OL</sub> = 1mA	1.5	_	0.23	0.31	_	0.37	
				$I_{OL} = 2.6 mA$	3.0	_	0.23	0.31	—	0.33	
Input Leakage Current	IN	_	V <sub>IN</sub> = V <sub>CC</sub>	or GND	3.6	_	_	± 0.1	_	± 1.0	
Quiescent Supply Current	<sup>l</sup> cc	_	V <sub>IN</sub> = V <sub>CC</sub>	or GND	3.6	_	_	1.0	_	10.0	μΑ

### AC ELECTRICAL CHARACTERISTICS ( $C_L = 15pF$ , Input $t_r = t_f = 6ns$ , $V_{CC} = 3.3 \pm 0.3 V$ )

CHADACTEDISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION	7	UNIT		
CHARACTERISTIC			TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Transition	tTLH				5.0	9.0	ns
Time	tTHL		<del>-</del>		3.0	3.0	113
Propagation	t <sub>PLH</sub>				7.5	13.0	ns
Delay Time	t <sub>PHL</sub>		<del>_</del>	_	/.5	13.0	113

#### AC ELECTRICAL CHARACTERISTICS ( $C_L = 25pF$ , Input $t_r = t_f = 6ns$ )

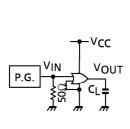
CHARACTERISTIC	SYMBOL	TEST	TEST CONDITION		Ta = 25°C			Ta = -4		
CHARACTERISTIC	STIVIBUL	CIR- CUIT		Vcc	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
Output Transition	+			1.0	_	70	170	_	240	
Output Transition Time	t <sub>TLH</sub>	_	_	1.5	—	25	45	_	55	ns
Time	<sup>t</sup> THL			3.0	l —	10	15	_	20	
Dropogation	4			1.0	_	70	170	_	210	
Propagation	t <sub>PLH</sub>	_	<del>-</del>	1.5	l —	25	45	<b> </b>	55	ns
Delay Time	<sup>t</sup> PHL			3.0	—	10	15	_	20	
Input Capacitance	CIN	_	<del></del>		_	5	10	_	10	
Power Dissipation Capacitance	C <sub>PD</sub>		Note (1)		_	10	_	_	_	pF

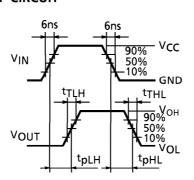
Note (1): C<sub>PD</sub> defined as the value of internal equivalent capacitance of IC which is calculated from the operating current consumption without load (refer to Test Circuit).

Average operating current can be obtained by the equation as follows.

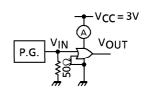
ICC (opr) = CPD·VCC·fIN + ICC

#### SWITCHING CHARACTERISTICS TEST CIRCUIT





ICC (opr) TEST CIRCUIT

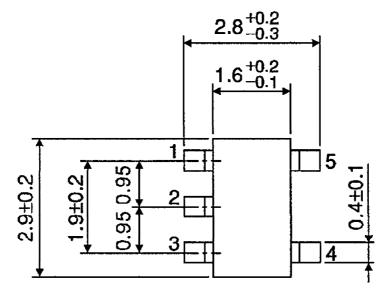


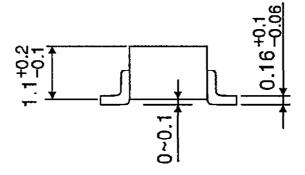
Input waveform is the same as that in case of switching characteristics test.

# PACKAGE DIMENSIONS

SSOP5-P-0.95

Unit: mm



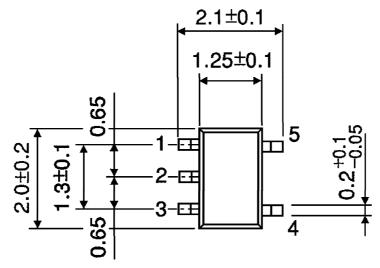


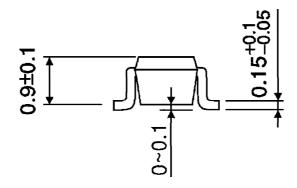
Weight: 0.016g (Typ.)

# PACKAGE DIMENSIONS

SSOP5-P-0.65A

Unit: mm





Weight: 0.006g (Typ.)

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000707EBA

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